

201117929 EFM8 BB3 Silicon Revision D

PRCN Issue Date: 11/17/2020 Effective Date: 2/23/2021

PCN Type: Product Revision

Description of Change

Silicon Labs is pleased to announce the release of revision D of EFM8BB3 devices.

This release is accompanied by version 1.4 of the EFM8BB3 Datasheet, version 1.0 of the EFM8BB3 errata, and version 0.7 of the EFM8BB3 reference manual.

Note: After the effective date of the PRCN, Silicon Labs reserves the right not to accept orders for the old revision.

Reason for Change

Revision D devices resolve 2 errata issues related to LIN communication and external crystal oscillators. LIN communication will now function correctly as errata item UART1_E101 has been resolved. External crystal oscillators are now supported on revision D devices as errata item XOSC_E101 has been resolved.

Please view the version 1.0 of the errata for details on the errata items.

Please see the revision history section of version 1.4 of the datasheet for details on updates made.

Please see the revision history section of version 0.7 of the reference manual details on updates made.

Impact on Form, Fit, Function, Quality, Reliability

There is no impact for form, fit, quality or reliability. Function is impacted as described in the change reason section and relevant errata items.

Product Identification

Existing Part #	Replacement Part #	DropInCompInd.
EFM8BB31F16A-C-4QFN24	EFM8BB31F16A-D-4QFN24	Yes
EFM8BB31F16A-C-4QFN24R	EFM8BB31F16A-D-4QFN24R	Yes
EFM8BB31F16A-C-5QFN32	EFM8BB31F16A-D-5QFN32	Yes
EFM8BB31F16A-C-5QFN32R	EFM8BB31F16A-D-5QFN32R	Yes
EFM8BB31F16G-C-QFN24	EFM8BB31F16G-D-QFN24	Yes
EFM8BB31F16G-C-QFN24R	EFM8BB31F16G-D-QFN24R	Yes
EFM8BB31F16G-C-QFN32	EFM8BB31F16G-D-QFN32	Yes
EFM8BB31F16G-C-QFN32R	EFM8BB31F16G-D-QFN32R	Yes
EFM8BB31F16G-C-QFP32	EFM8BB31F16G-D-QFP32	Yes
EFM8BB31F16G-C-QFP32R	EFM8BB31F16G-D-QFP32R	Yes
EFM8BB31F16G-C-QSOP24	EFM8BB31F16G-D-QSOP24	Yes
EFM8BB31F16G-C-QSOP24R	EFM8BB31F16G-D-QSOP24R	Yes
EFM8BB31F16I-C-4QFN24	EFM8BB31F16I-D-4QFN24	Yes
EFM8BB31F16I-C-4QFN24R	EFM8BB31F16I-D-4QFN24R	Yes
EFM8BB31F16I-C-5QFN32	EFM8BB31F16I-D-5QFN32	Yes
EFM8BB31F16I-C-5QFN32R	EFM8BB31F16I-D-5QFN32R	Yes
EFM8BB31F16I-C-QFN24	EFM8BB31F16I-D-QFN24	Yes
EFM8BB31F16I-C-QFN24R	EFM8BB31F16I-D-QFN24R	Yes
EFM8BB31F16I-C-QFN32	EFM8BB31F16I-D-QFN32	Yes
EFM8BB31F16I-C-QFN32R	EFM8BB31F16I-D-QFN32R	Yes
EFM8BB31F16I-C-QFP32	EFM8BB31F16I-D-QFP32	Yes
EFM8BB31F16I-C-QFP32R	EFM8BB31F16I-D-QFP32R	Yes

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EFM8BB31F16I-C-QSOP24 EFM8BB31F16I-D-QSOP24
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EFM8BB31F32A-C-5QFN32R EFM8BB31F32A-D-5QFN32R Yes
EFM8BB31F32G-C-QFN24 EFM8BB31F32G-D-QFN24
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                      EFM8BB31F32G-D-QFN32
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                      EFM8BB31F32G-D-QFP32
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                                             Yes
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                      EFM8BB31F32I-D-QFN32
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                      EFM8BB31F64G-D-QFN24
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EFM8BB31F64I-C-QSOP24R EFM8BB31F64I-D-QSOP24R Yes
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Kit Identification

Kits impacted by the above product are listed below. Orders for the following obsolete kits will no longer be accepted.

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Existing Kit # Replacement Kit #
NA NA
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Last Date of Unchanged Product: 2/23/2021

Qualification Samples

Commercial and industrial grade device samples available, automotive grade samples available upon request.

Customer Response

Lack of acknowledgment of the PCN within 30 days constitutes acceptance of the change, Ref. JEDEC-J-STD-046.

To request further data or inquire about this notification, please contact your Silicon Labs sales representative. A list of Silicon Labs sales representatives is available at http://www.silabs.com.

Customers may approve early PCN acceptance by emailing approval, along with PCN # to PCNEarlyAcceptance@silabs.com

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Qualification Data

See appendix.

Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
	ccelerated Environment Stress	Tests - 32TQFP-	ASECL asser	nbly			
HAST	JA110		Q038332	0/82	1		
	130°C, 85%RH	3 lots, N=>77	Q038502	0/82	1	3 lots	Pass
	Vcc=3.6V, 96 hours		Q038506	0/82	1	0/246	
UHAST	JA110		Q038334	0/82	1		
	130°C, 85%RH	3 lots, N=>77	Q038504	0/82	1	3 lots	Pass
	96 hours		Q038508	0/80	1	0/244	0.000
Temp Cycle	JA104		Q038333	0/86	1		
	Cond C: -65°C to 150°C	3 lots, N=>77	Q038501	0/81	1	3 lots	Pass
	500 cycles		Q038505	0/81	1	0/248	
HTSL	JA103		Q038315	0/46	1		
	150°C, 1000hr	1 lot, N=>45	Q038503	0/50	1	3 lots	Pass
	Services & VIII (1997) CU		Q038507	0/50	1	0/146	
Test Group A - A	ccelerated Environment Stress	Tests - 24 QSOP	-UTACTH ass	sembly			
HAST	JA110		Q038411	0/78	1		
	130°C, 85%RH	3 lots, N=>77	Q036513	0/80	1	3 lots	Pass
	Vcc=3.6V, 96 hours		Q036515	0/80	1	0/238	
UHAST	JA110		Q038412	0/78	1		
	130°C, 85%RH	3 lots, N=>77	Q036526	0/80	1	3 lots	Pass
	96 hours		Q036527	0/80	- 1	0/238	
Temp Cycle	JA104		Q038413	0/79	1		
	Cond C: -65°C to 150°C	3 lots, N=>77	Q036523	0/80	1	3 lots	Pass
	500 cycles	7.0000000000000000000000000000000000000	Q036524	0/80	1	0/239	
HTSL	JA103		Q038366	0/50	1		
	150°C, 1000hr	1 lot, N=>45	Q036520	0/28	1	3 lots	Pass
		1 1004 110 110	Q036521	0/28	1	0/106	. 550
Test Group A - A	ccelerated Environment Stress	Tests - 24-QFN-A					
HAST	JA110		Q038217	0/80	-1		
	130°C, 85%RH	3 lots, N=>77	Q038218	0/80	1	3 lots	Pass
	Vcc=3.6V, 96 hours	200000000000000000000000000000000000000	Q038219	0/80	1	0/240	
UHAST	JA110		Q038223	0/80	1		
	130°C, 85%RH	3 lots, N=>77	Q038224	0/80	1	3 lots	Pass
	96 hours		Q038225	0/80	1	0/240	
Temp Cycle	JA104		Q038220	0/80	1		
	Cond C: -65°C to 150°C	3 lots, N=>77	Q038221	0/80	1	3 lots	Pass
	500 cycles	Comment of the Comment	Q038222	0/80	1	0/240	. 000
HTSL	JA103	1	Q038181	0/48	1	0.240	
	150°C, 1000hr	1 lot, N=>45	Q038182	0/48	1	3 lots	Pass
	100 0, 100011	1 101, 14-7-40	Q038183	0/48	1	0/144	. 800

EFM8BB3* AEC-Q100 Qualification Report

Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
Test Group A - A	ccelerated Environment Stress	s Tests - 32-TQFN-	UTACTH ass	sembly			
HAST	JA110		Q038160	0/84	1		
	130°C, 85%RH	3 lots, N=>77	Q038359	0/84	1	4 lots	Pass
	Vcc=3.6V, 96 hours		Q038363	0/85	1	0/340	
			Q039097	0/87	1	183333577	
UHAST	JA110		Q038161	0/85	1		
	130°C, 85%RH	3 lots, N=>77	Q038360	0/85	1	4 lots	Pass
	96 hours		Q038364	0/80	1	0/337	
			Q039095	0/87	1		
Temp Cycle	JA104		Q038158	0/85	1		
	Cond C: -65°C to 150°C	3 lots, N=>77	Q038357	0/85	1	4 lots	Pass
	500 cycles		Q038361	0/85	1	0/353	
	189		Q039098	0/98	1		
HTSL	JA103		Q038159	0/50	1		
	150°C, 1000hr	1 lot, N=>45	Q038358	0/49	1	3 lots	Pass
		3.353(33)(35)	Q039096	0/41	1	0/140	1100000
Test Group B - A	ccelerated Lifetime Simulation	Tests				-	
HTOL	JA108		Q038228	0/84	-		
	T _J ≥ 125°C, Dynamic	3 lots, N=>77	Q038640	0/84		3 lots	Pass
	Vcc=3.6V, 1000 hours	2.5	Q038861	0/90		0/258	
LTOL	JA108						
	-10°C, Dynamic	1 lot, N=>77	Q036550	0/35		1 lots	Pass
	Vcc=3.6V, 1000 hours					0/35	
ELFR	AEC-Q100-008		Q038355	0/842			
	T _J ≥ 125°C, Dynamic	3 lots, N=>800	Q046686	0/849		3 lots	Pass
	Vcc=3.6V, 48 hours	E-217-257-1207-1208	Q038785	0/840		0/2531	
Data Retention	AEC-Q100-005	1	Q038230	0/44			
High Temp	150°C, 1000 hours	3 lots, N=>39	Q038627	0/45		3 lots	Pass
			Q038848	0/49		0/138	
Data Retention	AEC-Q100-005		Q038314	0/39			
Low Temp	25°C, 1000 hours	3 lots, N=>38	Q038622	0/40		3 lots	Pass
			Q038846	0/45		0/124	- 4150
NVM P/E Cycling	AEC-Q100-005		Q038193				
High Temp	85°C, 1000 hours	3 lots, N=>77	Q038588	0/140		3 lots	Pass
	00 0, 1000 mone	2.000, 11	Q038790	0/136		0/416	. 660
NVM P/E Cycling	AEC-Q100-005	1	Q038194	0/40		41.7.74	
Low Temp	25°C, 1000 hours	3 lots, N=>77	Q038589	0/40		3 lots	Pass
	25 O, 1000 Hours	3 1013, 14-277	Q038788			0/125	r e 55

EFM8BB3* AEC-Q100 Qualification Report

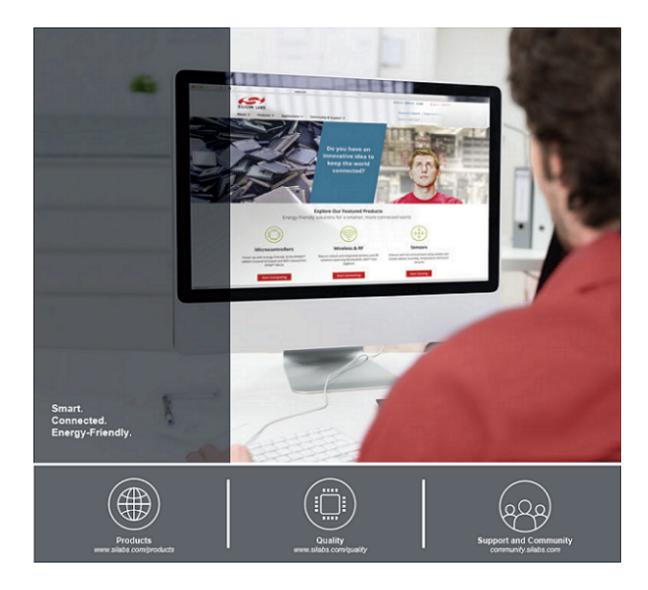
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
Test Group C - Pa	ckage Assembly Integrity T	ests					
Wire Bond Pull	M-STD-883						
	Performed post-TC	5 units, N=>30	Q038389	0/5	2	1 lots 0/5	Pass
Wire Bond Pull	M-STD-883						
	Performed post-TC	5 units, N=>30	Q038470	0/5	3	1 lots 0/5	Pass
Wire Bond Pull	M-STD-883						
	Performed post-TC	5 units, N=>30	Q038480	0/15	4	1 lots 0/15	Pass
Wire Bond Pull	M-STD-883						
	Performed post-TC	5 units, N=>30	Q038388	0/5	5	2 lots	Pass
			Q039289	0/5	5	0/10	
	ectrical Verification						
ESD-HBM	AEC-Q100-002	1 lot, N=>3	Q043453		2	4 kV	Class 3A
ESD-CDM	AEC-Q100-011		Q043452		2	1000 V	Class C6
			Q038118		3	1000 V	Class C6
		1 lot, N=>3	Q043616		4	1000 V	Class C6
			Q043615		5	1000 V	Class C6
Latch Up	AEC-Q100-004		Q043450	25 °C	2		Pass
	±100mA Overvoltage = 5.4V	1 lot, N=>6	Q043451	105 °C	2		Pass
Electromagnetic Compatibility	SAE J1752	1 lot, N=>1	Q039317				Pass

Notes:

- 1. Parts are Pre-conditioned at MSL2/260°C
- 2. 32-TQFP
- 3.24-QSOP
- 4. 24-QFN
- 5. 32-TQFN

	This report applies to the following part number	bers:
EFM8BB31F*G-D-QFN24	EFM8BB31F*I-D-QFN24	EFM8BB31F*A-D-4QFN24
EFM8BB31F*G-D-QFN32	EFM8BB31F*I-D-QFN32	EFM8BB31F*A-D-5QFN32
EFM8BB31F*G-D-QFP32	EFM8BB31F*I-D-QFP32	EFM8BB31F*I-D-4QFN24
EFM8BB31F*G-D-QSOP24	EFM8BB31F*I-D-QSOP24	EFM8BB31F*I-D-5QFN32

EFM8BB3* AEC-Q100 Qualification Report



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